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PATENT NUMBER and
ISSUE DATE

U.S. UTILITY Patent Application

APPL NUM	FILING DATE	CLASS	SUBCLASS	GAU	EXAMINER
10084987	02/28/2002	356	356	2877	1-011105E

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**CONTINUING DATA VERIFIED:

** FOREIGN APPLICATIONS VERIFIED:

PG-PUB DO NOT PUBLISH ☒

RESCIND ☐

Foreign priority claimed ☐ yes ☐ no

35 USC 119 conditions met ☐ yes ☐ no

Verified and Acknowledged Examiners's initials

ATTORNEY DOCKET NO

2000.092400

TITLE : Method of using high yielding spectra scatterometry measurements to control semiconductor manufacturing processes, and systems for accomplishing same

U.S. DEPT. OF COMM./PAT. & TM.-PTO-436L (Rev. 12-94)

NOTICE OF ALLOWANCE MAILED		CLAIMS ALLOWED	
		Total Claims	Print Claim for O.G.
Assistant Examiner		DRAWING	
		Sheet 1 of 1	Print Fig.
Amount Due		Application Examiner	
Date Paid			
<input type="checkbox"/> TERMINAL DISCLAIMER		PREPARED FOR ISSUE	
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